Se	arch	Not	es	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/658,868	YANG, SAM	
Examiner	Art Unit	
B. Chen	1762	

SEARCHED			
Class	Subclass	Date	Examiner
427	250	9/28/2005	ВС
	255.31		
	376.2		
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
427	250	9/28/2005	ВС
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west	9/28/2005	BC
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